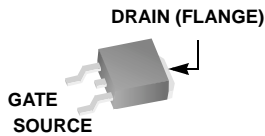


**30V, 0.007 Ohm, 35A, N-Channel
UltraFET® Trench Power MOSFET**

UltraFET® Trench from Fairchild is a new advanced MOSFET technology that achieves the lowest possible on-resistance per silicon area while maintaining fast switching and low gate charge. The reduced conduction and switching losses extend battery life in notebook PCs, cellular telephones and other portable information appliances and improve the overall efficiency of high frequency DC-DC converters used to power the latest microprocessors.

Packaging

ISL9N2357D3ST
JEDEC TO-252AA

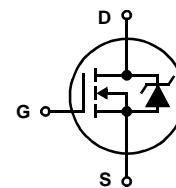


UltraFET® Trench

Features

- $r_{DS(ON)} = 0.006\Omega$ Typical, $V_{GS} = 10V$
- Q_g Total 85nC Typical, $V_{GS} = 10V$
- Q_{gd} 16nC Typical
- C_{ISS} 5600pF Typical

Symbol



Ordering Information

| PART NUMBER | PACKAGE | BRAND |
|---------------|----------|--------|
| ISL9N2357D3ST | TO-252AA | N2357D |

NOTE: When ordering, use the entire part number.
e.g., ISL9N2357D3ST.

Absolute Maximum Ratings $T_C = 25^\circ C$, Unless Otherwise Specified

| SYMBOL | PARAMETER | ISL9N2357D3ST | UNITS |
|----------------|---|---------------|---------------|
| V_{DSS} | Drain to Source Voltage (Note 1) | 30 | V |
| V_{DGR} | Drain to Gate Voltage ($R_{GS} = 20k\Omega$) (Note 1) | 30 | V |
| V_{GS} | Gate to Source Voltage | ± 20 | V |
| I_D | Drain Current | | |
| I_D | Continuous ($T_C = 25^\circ C$, $V_{GS} = 10V$) (Figure 2) | 35 | A |
| I_D | Continuous ($T_C = 100^\circ C$, $V_{GS} = 10V$) | 35 | A |
| I_{DM} | Pulsed Drain Current | Figure 4 | A |
| P_D | Power Dissipation | 100 | W |
| | Derate Above $25^\circ C$ | 0.67 | W/ $^\circ C$ |
| T_J, T_{STG} | Operating and Storage Temperature | -55 to 175 | $^\circ C$ |
| T_L | Maximum Temperature for Soldering | 300 | $^\circ C$ |
| T_{pkg} | Leads at 0.063in (1.6mm) from Case for 10s Package Body for 10s, See Techbrief TB334 | 260 | $^\circ C$ |

THERMAL SPECIFICATIONS

| | | | |
|-----------------|---|-----|--------------|
| $R_{\theta JC}$ | Thermal Resistance Junction to Case, TO-252 | 1.5 | $^\circ C/W$ |
| $R_{\theta JA}$ | Thermal Resistance Junction to Ambient TO-252 | 100 | $^\circ C/W$ |

NOTE:

1. $T_J = 25^\circ C$ to $150^\circ C$.

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

ISL9N2357D3ST

Electrical Specifications $T_C = 25^\circ\text{C}$, Unless Otherwise Specified

| PARAMETER | SYMBOL | TEST CONDITIONS | MIN | TYP | MAX | UNITS | |
|---|--------------|---|--|-------|-----------|---------------|----|
| OFF STATE SPECIFICATIONS | | | | | | | |
| Drain to Source Breakdown Voltage | BV_{DSS} | $I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$ (Figure 9) | 30 | - | - | V | |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$ | - | - | 1 | μA | |
| | | $V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$, $T_C = 150^\circ\text{C}$ | - | - | 250 | μA | |
| Gate to Source Leakage Current | I_{GSS} | $V_{GS} = \pm 20\text{V}$ | - | - | ± 100 | nA | |
| ON STATE SPECIFICATIONS | | | | | | | |
| Gate to Source Threshold Voltage | $V_{GS(TH)}$ | $V_{GS} = V_{DS}$, $I_D = 250\mu\text{A}$ (Figure 8) | 2 | - | 4 | V | |
| Drain to Source ON Resistance | $r_{DS(ON)}$ | $I_D = 35\text{A}$, $V_{GS} = 10\text{V}$ (Figure 7) | - | 0.006 | 0.007 | Ω | |
| SWITCHING SPECIFICATIONS ($V_{GS} = 10\text{V}$) | | | | | | | |
| Turn-On Time | t_{ON} | $V_{DD} = 15\text{V}$, $I_D = 20\text{A}$ $V_{GS} = 10\text{V}$, $R_{GS} = 9.1\Omega$ (Figures 14, 15) | - | - | 144 | ns | |
| Turn-On Delay Time | $t_{d(ON)}$ | | - | 27 | - | ns | |
| Rise Time | t_r | | - | 69 | - | ns | |
| Turn-Off Delay Time | $t_{d(OFF)}$ | | - | 84 | - | ns | |
| Fall Time | t_f | | - | 53 | - | ns | |
| Turn-Off Time | t_{OFF} | | - | - | 207 | ns | |
| GATE CHARGE SPECIFICATIONS | | | | | | | |
| Total Gate Charge at 20V | $Q_{g(TOT)}$ | $V_{GS} = 0\text{V}$ to 20V | $V_{DD} = 15\text{V}$, $I_D = 20\text{A}$, $I_{g(REF)} = 1.0\text{mA}$ (Figures 11, 12, 13) | - | 172 | 258 | nC |
| Total Gate Charge at 10V | $Q_{g(10)}$ | $V_{GS} = 0\text{V}$ to 10V | | - | 85 | 130 | nC |
| Threshold Gate Charge | $Q_{g(TH)}$ | $V_{GS} = 0\text{V}$ to 2V | | - | 11 | 17 | nC |
| Gate to Source Gate Charge | Q_{gs} | | | - | 23 | - | nC |
| Gate to Drain "Miller" Charge | Q_{gd} | | | - | 16 | - | nC |
| CAPACITANCE SPECIFICATIONS | | | | | | | |
| Input Capacitance | C_{ISS} | $V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$, $f = 1\text{MHz}$ (Figure 10) | - | 5600 | - | pF | |
| Output Capacitance | C_{OSS} | | - | 526 | - | pF | |
| Reverse Transfer Capacitance | C_{RSS} | | - | 355 | - | pF | |

Source to Drain Diode Specifications

| PARAMETER | SYMBOL | TEST CONDITIONS | MIN | TYP | MAX | UNITS |
|-------------------------------|----------|--|-----|-----|------|-------|
| Source to Drain Diode Voltage | V_{SD} | $I_{SD} = 20\text{A}$ | - | - | 1.25 | V |
| | | $I_{SD} = 10\text{A}$ | - | - | 1.0 | V |
| Reverse Recovery Time | t_{rr} | $I_{SD} = 20\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$ | - | - | 34 | ns |
| Reverse Recovered Charge | Q_{RR} | $I_{SD} = 20\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$ | - | - | 29 | nC |

Typical Performance Curves

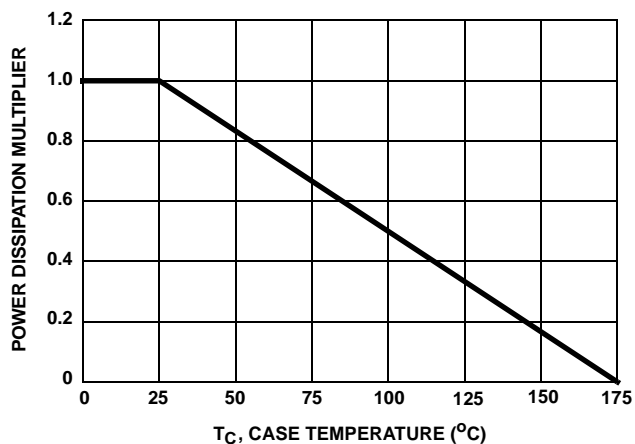


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

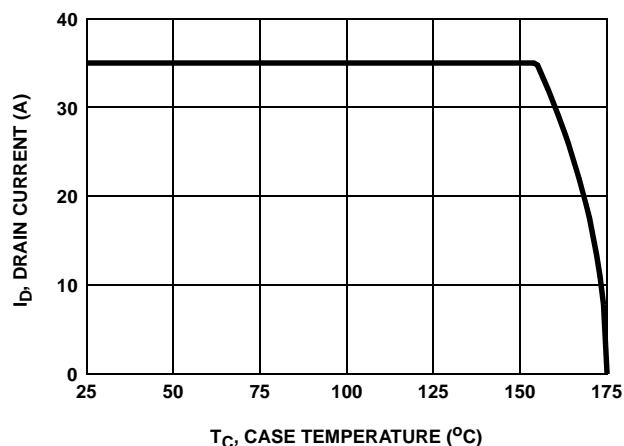


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

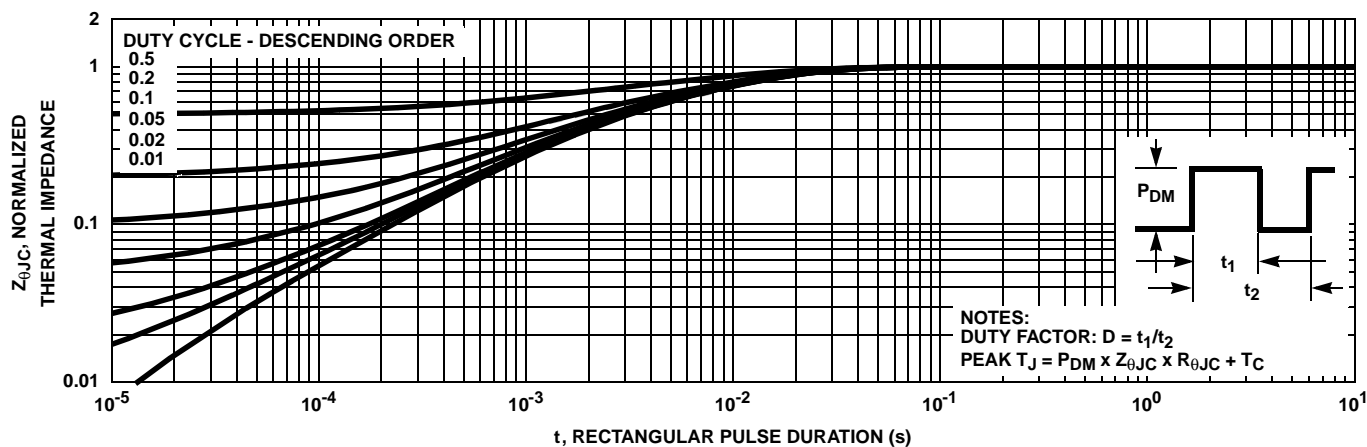


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

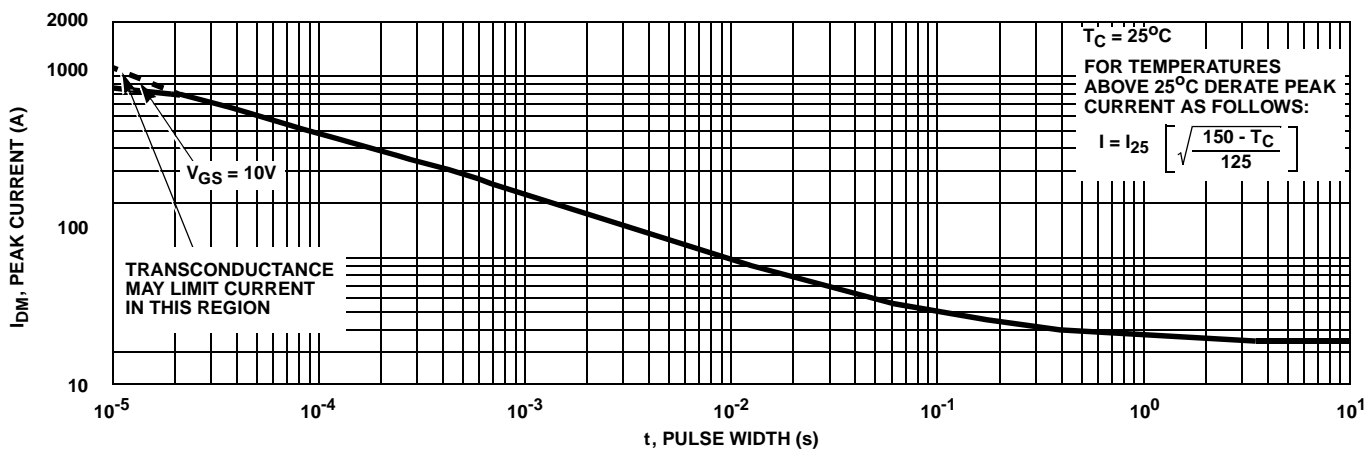


FIGURE 4. PEAK CURRENT CAPABILITY

Typical Performance Curves (Continued)

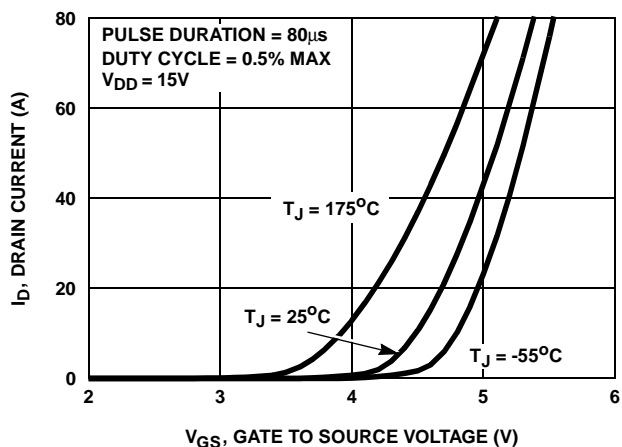


FIGURE 5. TRANSFER CHARACTERISTICS

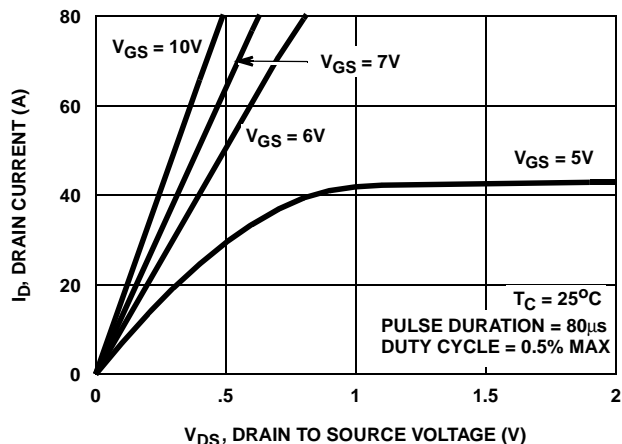


FIGURE 6. SATURATION CHARACTERISTICS

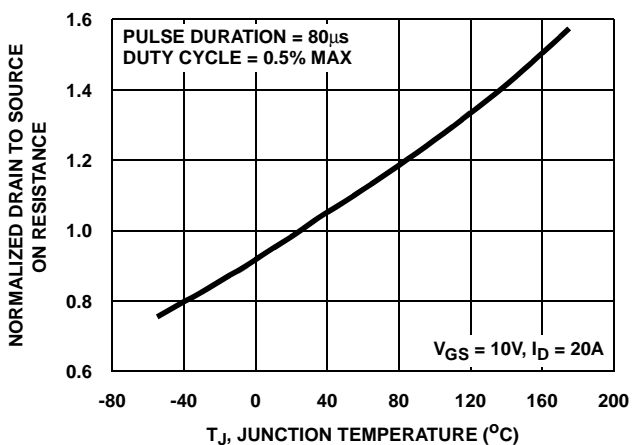


FIGURE 7. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

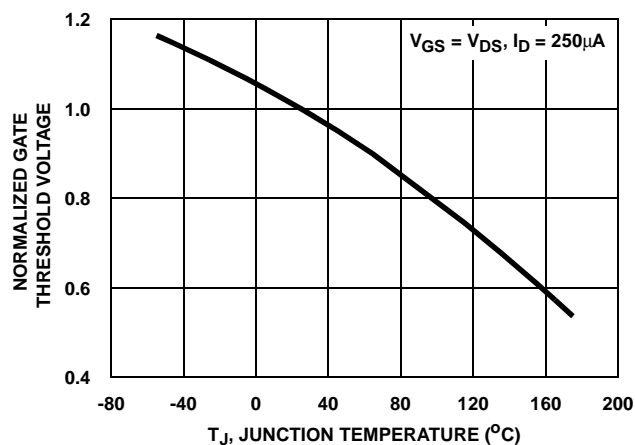


FIGURE 8. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE

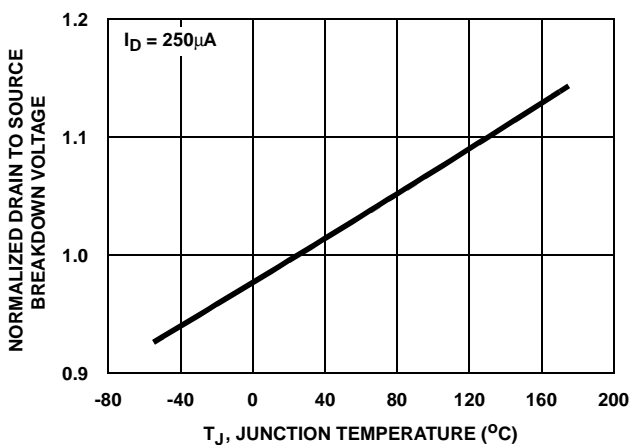


FIGURE 9. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

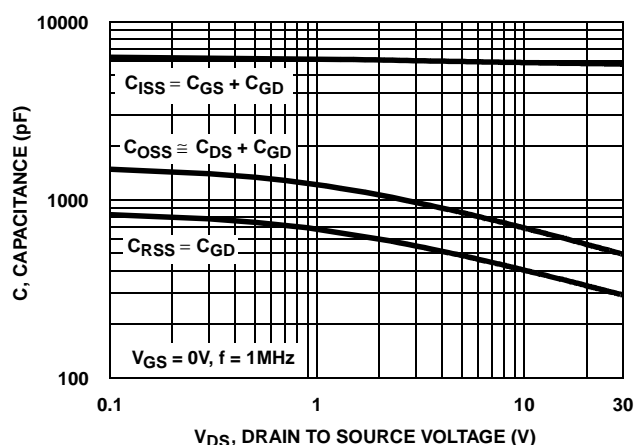
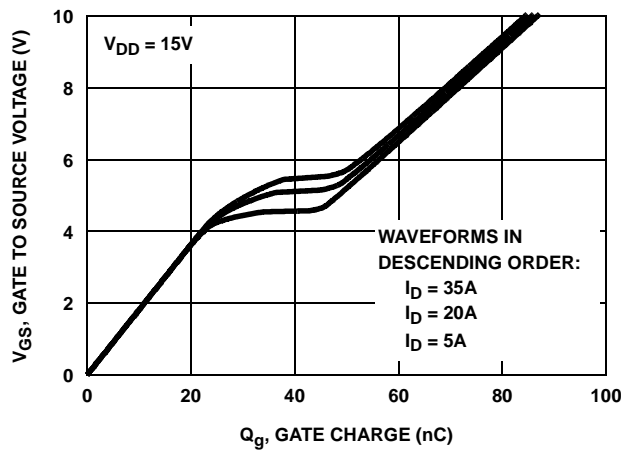


FIGURE 10. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

Typical Performance Curves (Continued)



NOTE: Refer to Fairchild Application Notes AN7254 and AN7260.

FIGURE 11. GATE CHARGE WAVEFORMS FOR CONSTANT GATE CURRENT

Test Circuits and Waveforms

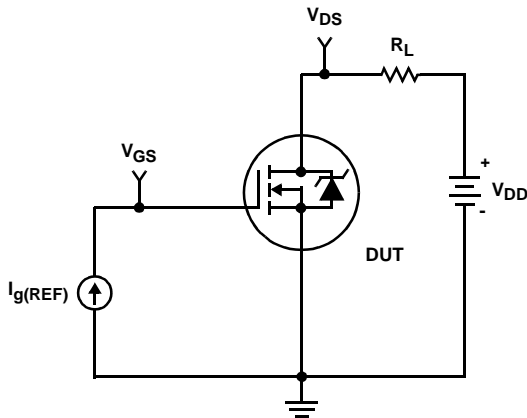


FIGURE 12. GATE CHARGE TEST CIRCUIT

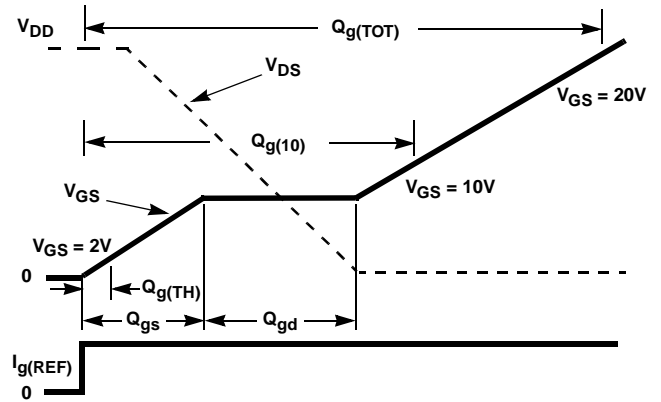


FIGURE 13. GATE CHARGE WAVEFORMS

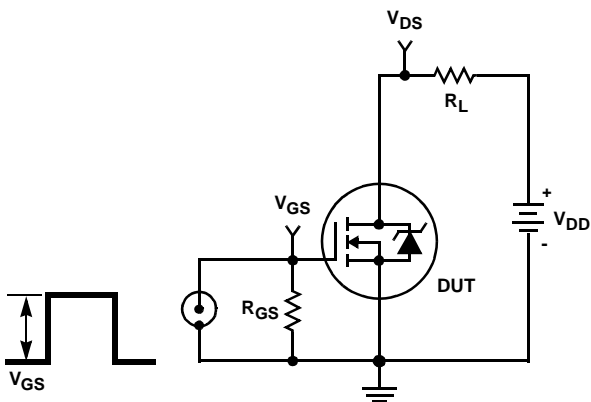


FIGURE 14. SWITCHING TIME TEST CIRCUIT

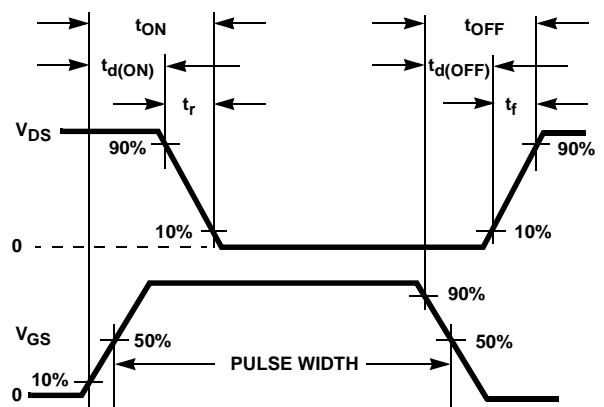


FIGURE 15. SWITCHING TIME WAVEFORM

ISL9N2357D3ST

PSPICE Electrical Model

.SUBCKT ISL9N2357 2 1 3 ; rev Aug 2000

CA 12 8 2.5e-9
 CB 15 14 2.1e-9
 CIN 6 8 5.2e-9

DBODY 7 5 DBODYMOD
 DBREAK 5 11 DBREAKMOD
 DPLCAP 10 5 DPLCAPMOD

EBREAK 11 7 17 18 33.39
 EDS 14 8 5 8 1
 EGS 13 8 6 8 1
 ESG 6 10 6 8 1
 EVTHRES 6 21 19 8 1
 EVTEMP 20 6 18 22 1

IT 8 17 1

LDRAIN 2 5 1.0e-9
 LGATE 1 9 4.3e-9
 LSOURCE 3 7 1.6e-9

MMED 16 6 8 8 MMEDMOD
 MSTRO 16 6 8 8 MSTROMOD
 MWEAK 16 21 8 8 MWEAKMOD

RBREAK 17 18 RBREAKMOD 1
 RDRAIN 50 16 RDRAINMOD 2.8e-3
 RGATE 9 20 1.68
 RLDRAIN 2 5 10
 RLGATE 1 9 43
 RLSOURCE 3 7 16
 RSLC1 5 51 RSLCMOD 1e-6
 RSLC2 5 50 1e3
 RSOURCE 8 7 RSOURCEMOD 1.8e-3
 RVTHRES 22 8 RVTHRESMOD 1
 RVTEMP 18 19 RVTEMPMOD 1

S1A 6 12 13 8 S1AMOD
 S1B 13 12 13 8 S1BMOD
 S2A 6 15 14 13 S2AMOD
 S2B 13 15 14 13 S2BMOD

VBAT 22 19 DC 1

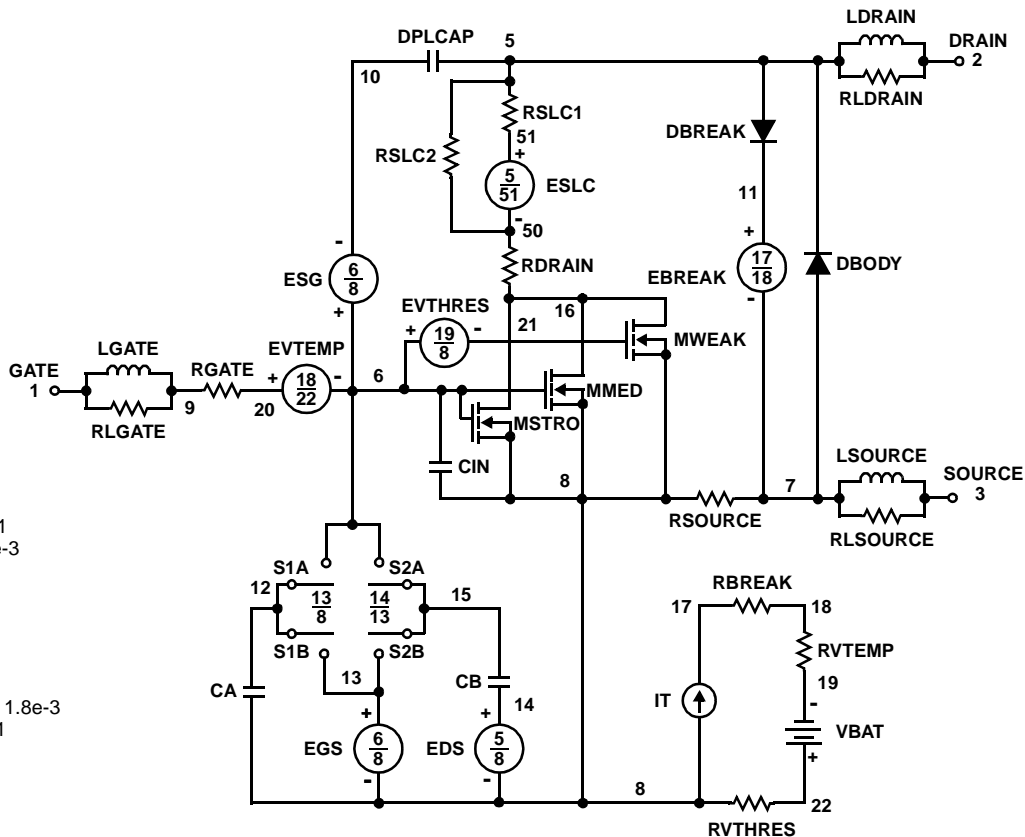
ESLC 51 50 VALUE={(V(5,51)/ABS(V(5,51)))*(PWR(V(5,51))/(1e-6*550),3))}

.MODEL DBODYMOD D (IS = 1.01e-12 RS = 3.5e-3 ikf = 15 TRS1 = 1.01e-3 TRS2 = 1.21e-6 CJO = 6.8e-10 TT = 6.7e-9 M = 0.35)
 .MODEL DBREAKMOD D (RS = 0.068 TRS1 = 1.12e-3 TRS2 = 1.25e-6)
 .MODEL DPLCAPMOD D (CJO = 8.5e-10 IS = 1e-30 N = 10 M = 0.31)
 .MODEL MMEDMOD NMOS (VTO = 3.5 KP = 6.0 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u RG = 1.68)
 .MODEL MSTROMOD NMOS (VTO = 4.1 KP = 110 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u)
 .MODEL MWEAKMOD NMOS (VTO = 3.0 KP = 0.03 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u RG = 16.8 RS = 0.1)
 .MODEL RBREAKMOD RES (TC1 = 1.01e-3 TC2 = 1.07e-7)
 .MODEL RDRAINMOD RES (TC1 = 4.5e-3 TC2 = 8.0e-6)
 .MODEL RSLCMOD RES (TC1 = 1.02e-4 TC2 = -1.13e-6)
 .MODEL RSOURCEMOD RES (TC1 = 1.0e-3 TC2 = 1e-6)
 .MODEL RVTHRESMOD RES (TC1 = -3.0e-3 TC2 = -1.5e-5)
 .MODEL RVTEMPMOD RES (TC1 = -4.0e-3 TC2 = 1.25e-6)

.MODEL S1AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -6.0 VOFF = -1.5)
 .MODEL S1BMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -1.5 VOFF = -6.0)
 .MODEL S2AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -0.7 VOFF = 0)
 .MODEL S2BMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = 0 VOFF = -0.7)

.ENDS

NOTE: For further discussion of the PSPICE model, consult **A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options**; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.



SABER Electrical Model

REV Aug 2000

template ISL9N2357 n2,n1,n3
electrical n2,n1,n3

```
{
var i iscl
dp..model dbodymod = (isl = 1.01e-12, rs = 3.5e-3, ikf=15, trs1 = 1.01e-3, trs2 = 1.21e-6, cjo = 6.8e-10, tt = 6.7e-9, m = 0.35)
dp..model dbreakmod = (rs = 0.068, trs1 = 1.12e-3, trs2 = 1.25e-6)
dp..model dplcapmod = (cjo = 8.5e-10, isl = 10e-30, nl=10, m = 0.31)
m..model mmedmod = (type=_n, vto = 3.5, kp = 6.0, is = 1e-30, tox = 1)
m..model mstrongmod = (type=_n, vto = 4.1, kp = 110, is = 1e-30, tox = 1)
m..model mweakmod = (type=_n, vto = 3.0, kp = 0.03, is = 1e-30, tox = 1, rs=0.1)
sw_vcsp..model s1amod = (ron = 1e-5, roff = 0.1, von = -6.0, voff = -1.5)
sw_vcsp..model s1bmod = (ron = 1e-5, roff = 0.1, von = -1.5, voff = -6.0)
sw_vcsp..model s2amod = (ron = 1e-5, roff = 0.1, von = -0.7, voff = 0)
sw_vcsp..model s2bmod = (ron = 1e-5, roff = 0.1, von = 0, voff = -0.7)
```

```
c.ca n12 n8 = 2.5e-9
c.cb n15 n14 = 2.1e-9
c.cin n6 n8 = 5.5e-9
```

```
dp.dbody n7 n5 = model=dbodymod
dp.dbreak n5 n11 = model=dbreakmod
dp.dplcap n10 n5 = model=dplcapmod
```

```
i.it n8 n17 = 1
```

```
l.l drain n2 n5 = 1.0e-9
l.l gate n1 n9 = 4.3e-9
l.l source n3 n7 = 1.6e-9
```

```
m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u
m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u
m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u
```

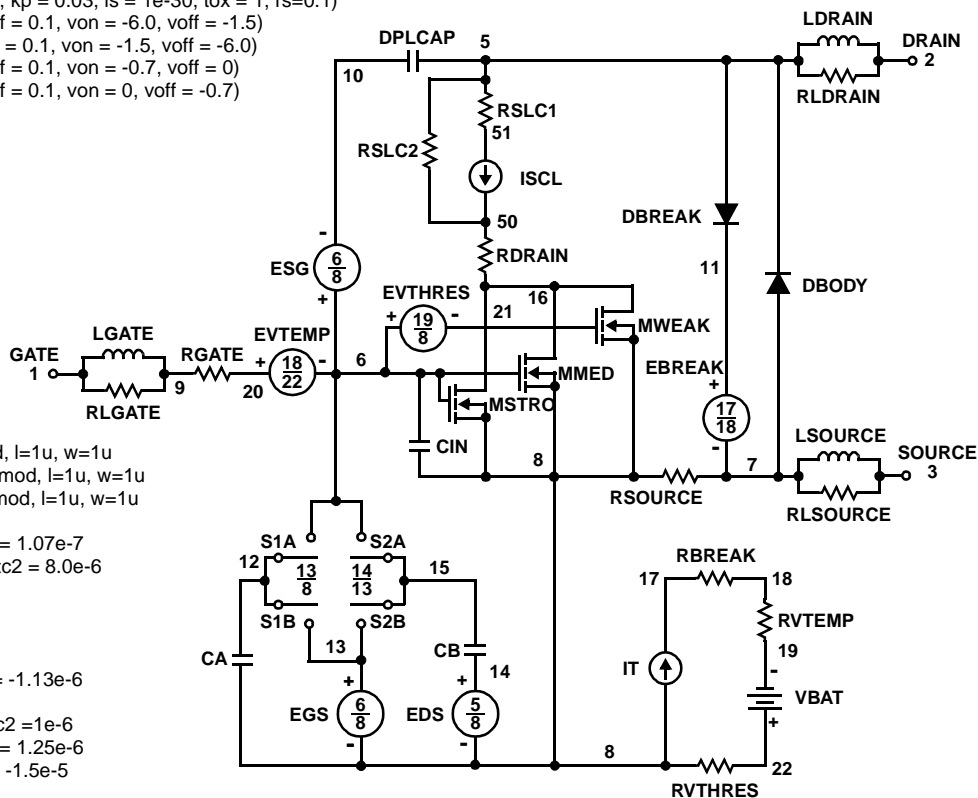
```
res.rbreak n17 n18 = 1, tc1 = 1.01e-3, tc2 = 1.07e-7
res.rdrain n50 n16 = 2.8e-3, tc1 = 4.5e-3, tc2 = 8.0e-6
res.rgate n9 n20 = 1.68
res.rldrain n2 n5 = 10
res.rlgate n1 n9 = 43
res.rlsource n3 n7 = 16
res.rslc1 n5 n51 = 1e-6, tc1 = 1.02e-4, tc2 = -1.13e-3
res.rslc2 n5 n50 = 1e3
res.rsource n8 n7 = 1.8e-3, tc1 = 1.0e-3, tc2 = 1e-6
res.rvtemp n18 n19 = 1, tc1 = -4.0e-3, tc2 = 1.25e-6
res.rvthres n22 n8 = 1, tc1 = -3.0e-3, tc2 = -1.5e-5
```

```
spe.ebreak n11 n7 n17 n18 = 33.39
spe.eds n14 n8 n5 n8 = 1
spe.egs n13 n8 n6 n8 = 1
spe.esg n6 n10 n6 n8 = 1
spe.evtemp n20 n6 n18 n22 = 1
spe.evthres n6 n21 n19 n8 = 1
```

```
sw_vcsp.s1a n6 n12 n13 n8 = model=s1amod
sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod
sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod
sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod
```

```
v.vbat n22 n19 = dc=1
```

```
equations {
i (n51->n50) +=iscl
iscl: v(n51,n50) = (((v(n5,n51))/(1e-9+abs(v(n5,n51)))))*((abs(v(n5,n51)*1e6/550))** 3)
}
}
```



SPICE Thermal Model

REV 23 March 2000

ISL9N2357T

CTHERM1 th 6 3.0e-3
 CHERM2 6 5 4.0e-3
 CHERM3 5 4 4.8e-3
 CHERM4 4 3 5.2e-3
 CHERM5 3 2 8.5e-3
 CHERM6 2 tl 5.0e-2

RATHERM1 th 6 3.5e-3
 RATHERM2 6 5 8.5e-3
 RATHERM3 5 4 5.7e-2
 RATHERM4 4 3 2.5e-1
 RATHERM5 3 2 4.3e-1
 RATHERM6 2 tl 4.5e-1

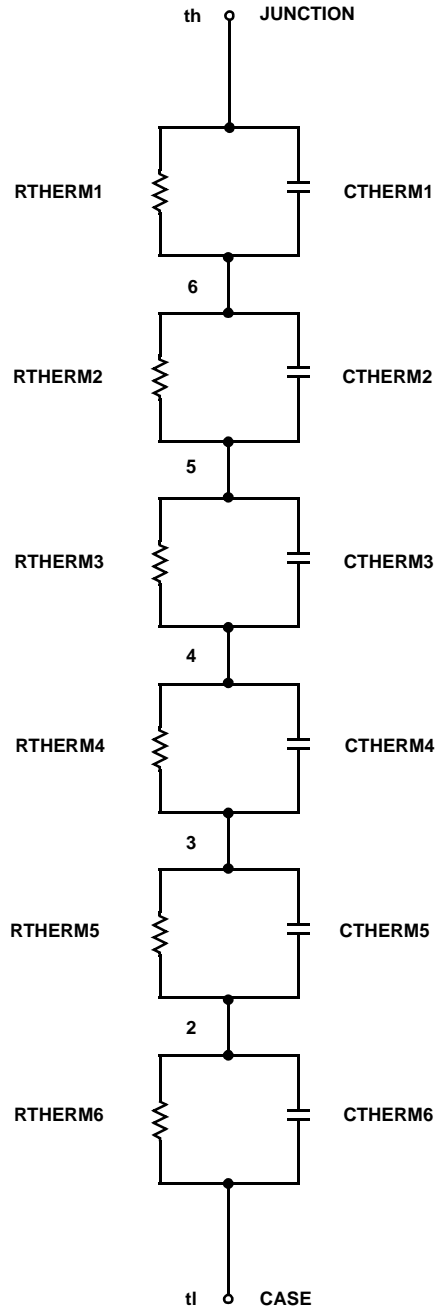
SABER Thermal Model

SABER thermal model ISL9N2357T

template thermal_model th tl
 thermal_c th, tl

```
{
ctherm.ctherm1 th 6 = 3.0e-3
ctherm.ctherm2 6 5 = 4.0e-3
ctherm.ctherm3 5 4 = 4.8e-3
ctherm.ctherm4 4 3 = 5.2e-3
ctherm.ctherm5 3 2 = 8.5e-3
ctherm.ctherm6 2 tl = 5.0e-2
```

```
rtherm.rtherm1 th 6 = 3.5e-3
rtherm.rtherm2 6 5 = 8.5e-3
rtherm.rtherm3 5 4 = 5.7e-2
rtherm.rtherm4 4 3 = 2.5e-1
rtherm.rtherm5 3 2 = 4.3e-1
rtherm.rtherm6 2 tl = 4.5e-1
}
```



TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

| | | | | |
|----------------------------------|---------------------------------|---------------------------------|------------------------------|-----------------------|
| ACE _x [™] | FAST [®] | MICROWIRE [™] | SILENT SWITCHER [®] | UHC [™] |
| Bottomless [™] | FAST _r [™] | OPTOLOGIC [®] | SMART START [™] | UltraFET [®] |
| CoolFET [™] | FRFET [™] | OPTOPLANAR [™] | SPM [™] | VCX [™] |
| CROSSVOLT [™] | GlobalOptoisolator [™] | PACMAN [™] | STAR*POWER [™] | |
| DenseTrench [™] | GTO [™] | POP [™] | Stealth [™] | |
| DOME [™] | HiSeC [™] | Power247 [™] | SuperSOT [™] -3 | |
| EcoSPARK [™] | I ² C [™] | PowerTrench [®] | SuperSOT [™] -6 | |
| E ² CMOS [™] | ISOPLANAR [™] | QFET [™] | SuperSOT [™] -8 | |
| EnSigna [™] | LittleFET [™] | QS [™] | SyncFET [™] | |
| FACT [™] | MicroFET [™] | QT Optoelectronics [™] | TinyLogic [™] | |
| FACT Quiet Series [™] | MicroPak [™] | Quiet Series [™] | TruTranslation [™] | |

STAR*POWER is used under license

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.
2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

| Datasheet Identification | Product Status | Definition |
|--------------------------|------------------------|---|
| Advance Information | Formative or In Design | This datasheet contains the design specifications for product development. Specifications may change in any manner without notice. |
| Preliminary | First Production | This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design. |
| No Identification Needed | Full Production | This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design. |
| Obsolete | Not In Production | This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only. |